Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination)r
10/601,085	JAIN ET AL.	
Examiner	Art Unit	
Matthew D. Matzek	1771	

SEARCHED				
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
,	DATE	EXMR	
	5/10/06	ИМ	
EAST	1/13/2005	ММ	
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,	5/10/66	ММ	
Inventor Search	1/13/2005	ММ	
ASSIGNEL	10/10/05	MA	
IDS	1/14/2005	ММ	
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